



Selected Enhanced Fidelity AIM Methods

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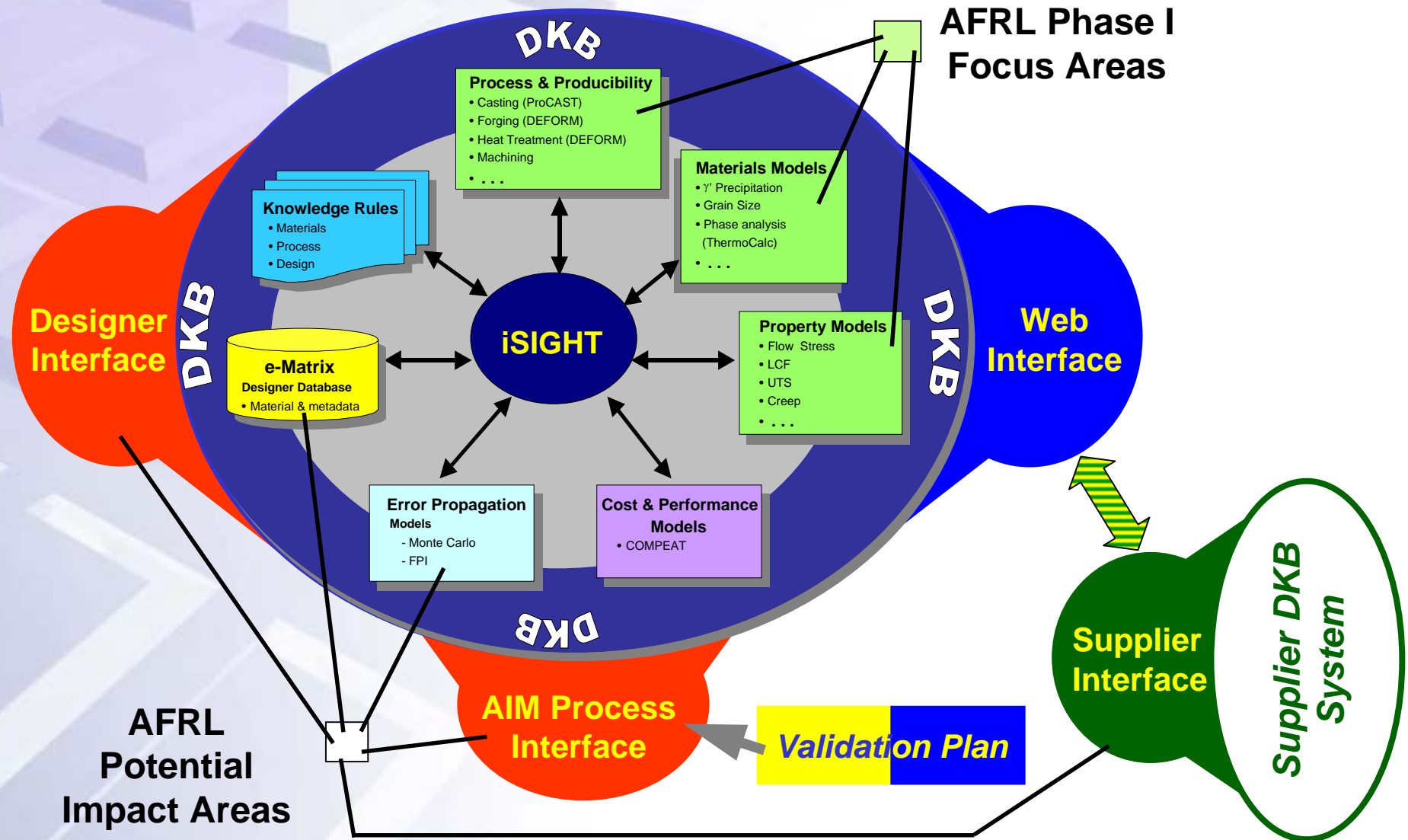
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AIM System Architecture





What About Phase II & Beyond?

In general, demand is for methods to treat unknown (without database)

Numerical descriptions needed for scope & fidelity in performance prediction (property minima & fracture are locally dominated)

These require development and adaptation to system architecture

Thus AFRL Focus:

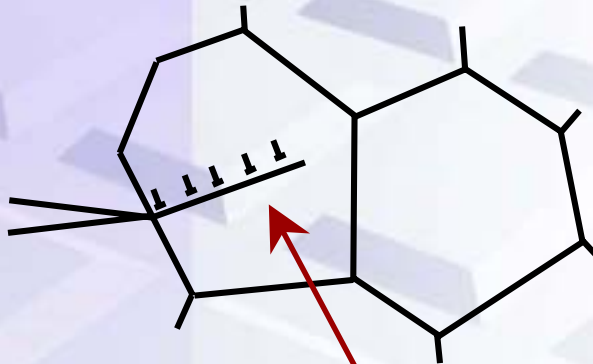
Prediction, quantification & representations of structure evolution & kinetics

Structure-sensitive numeric descriptions of properties

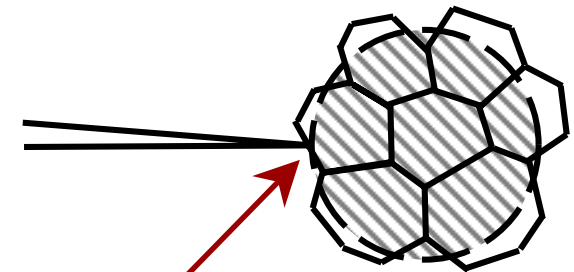
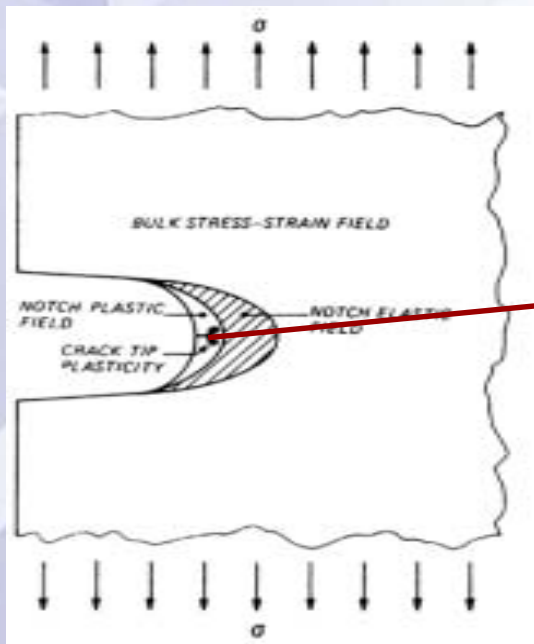
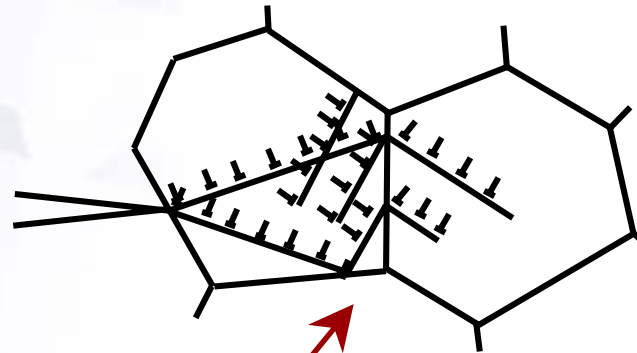
Overlay of 'homogenized' or 'fast-acting' models, validation/tuning procedures, & interlace with design/architecture

Need for Microstructure-Based Plasticity

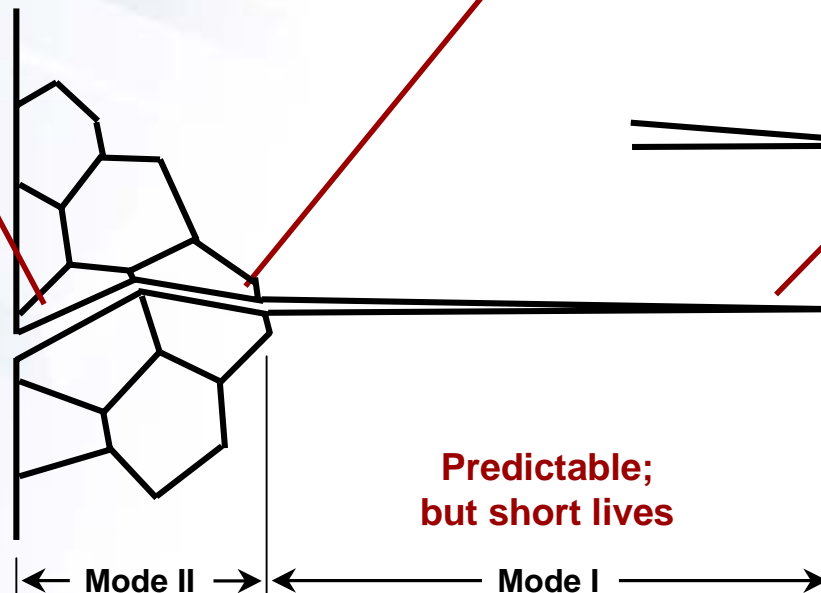
Short cracks & initiation;
slip & environment



'Longer' cracks;
microstructure &
local plasticity
dominated



Long cracks;
linear elastic
fracture
mechanics



Most of life;
unpredictable

Predictable;
but short lives

From Concepts to Realities

Briefings on Today's Progress

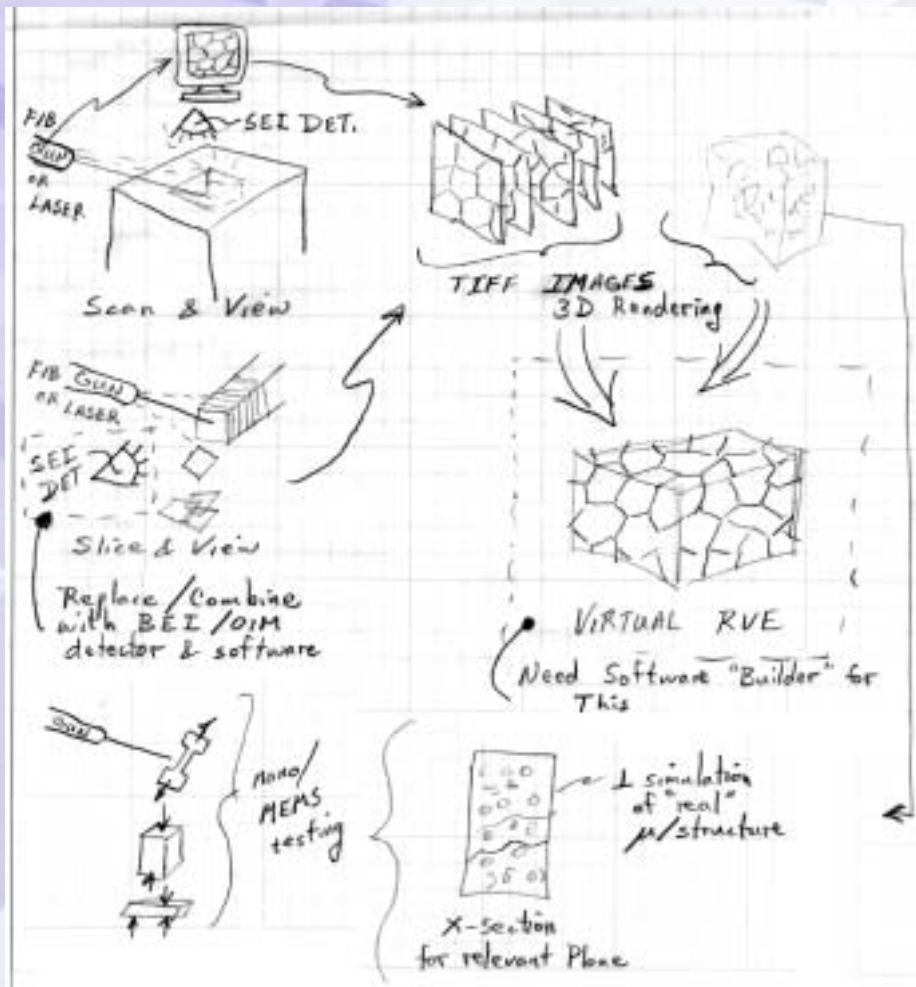
Phase Field (Simmons, 20min)

Plasticity Modeling (Parthasarathy, 20min)

Advanced Experimental Methods

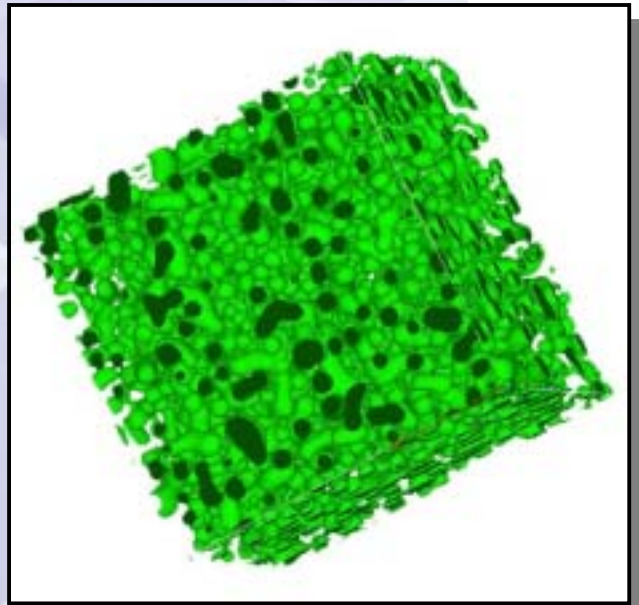
- 3D Quantification (Uchic, 10min)
- Representation (Simmons, 15min)
- Micro- & Nano-scale Tests (Uchic, 15min)

Broader View & Discussion
(Dimiduk, All)

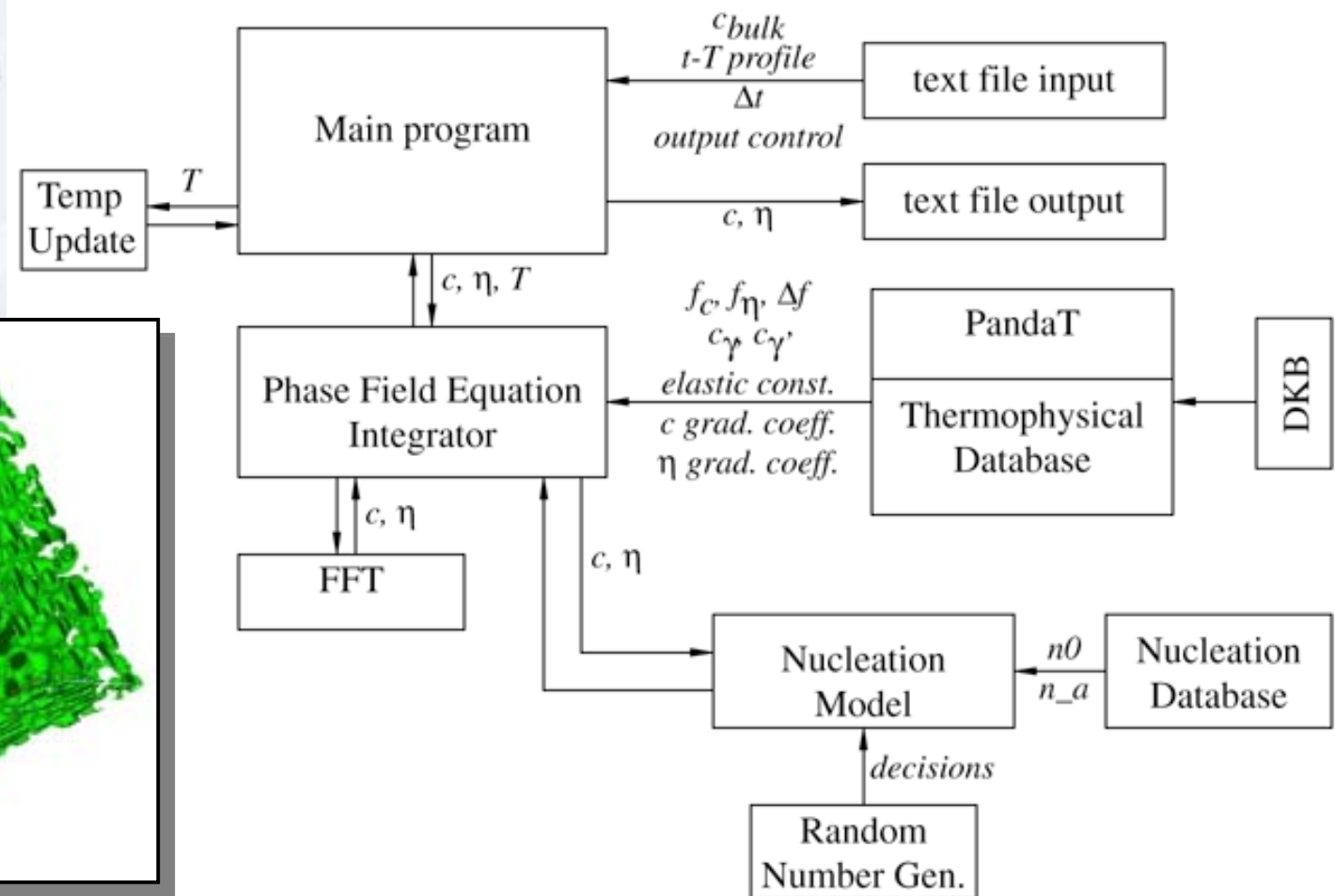


Last year's 'sketchy' concept

Architecture & Implementation of Phase Field Software



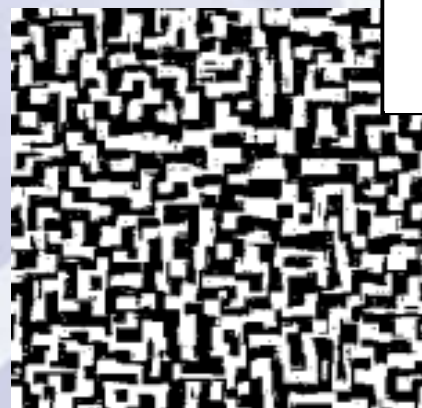
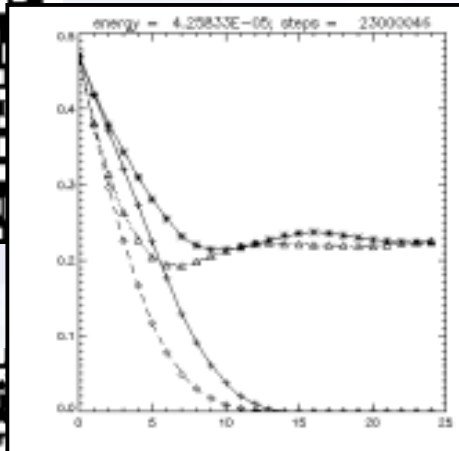
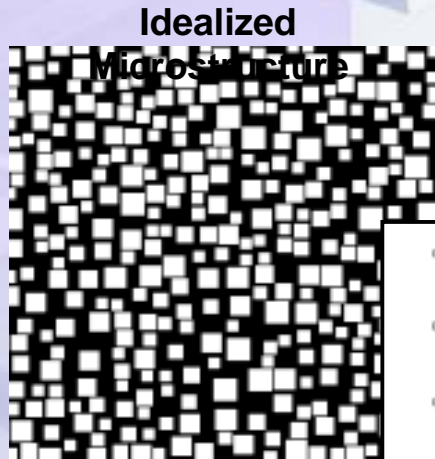
3D, Isothermal γ - γ' Coarsening



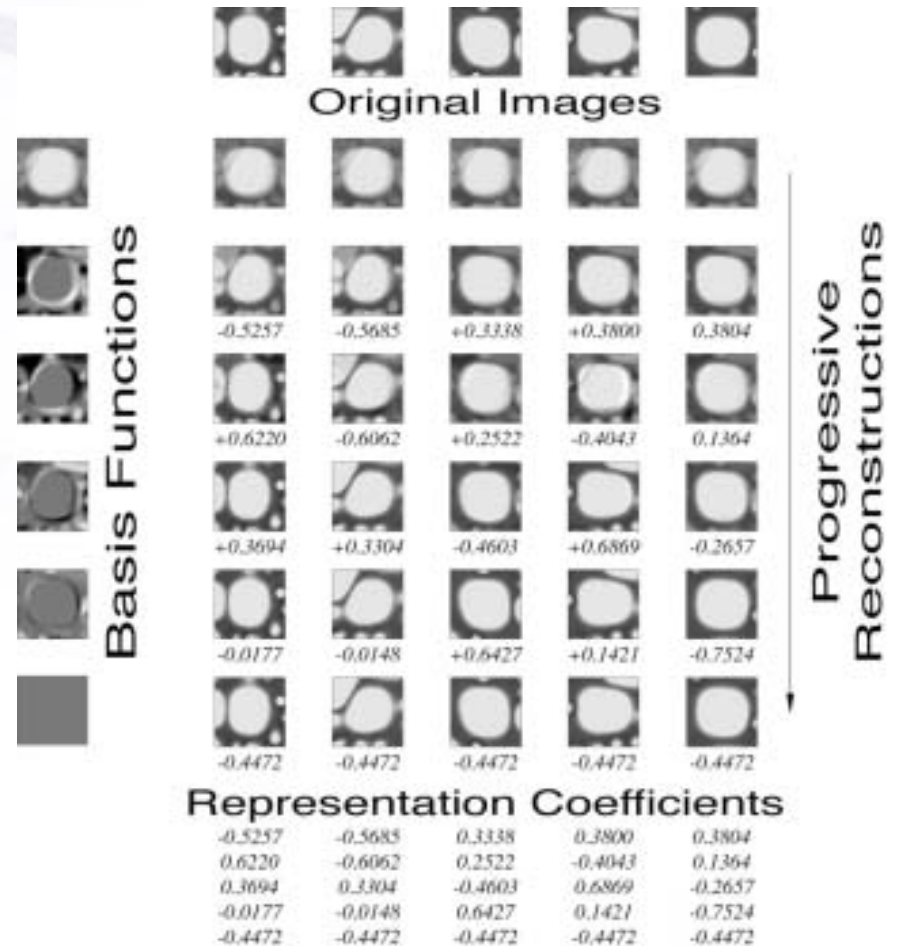
Clear framework identified...real dimensionality, thermodynamics evolving!

Microstructure Representations

2-Point & Lineal Path Functions



Monte Carlo
Reconstructed
Representative
Microstructure



Principal Component Analysis (KLT)

Revolutionary longer-term approach to capture all information contained in microstructure

Beyond Analytical Strength Models

Needs Development Within Atomistics

$$\sigma_y(C_i, T, \varepsilon, \dot{\varepsilon}, \dots) = f_\gamma \left(\frac{T_o}{T} \right) \left(\sum_i \frac{dc}{\sqrt{dC_i}} \sqrt{C_i} \right) + M f_t \left(\frac{\Gamma_{APB}}{b} \right)$$

Obtain by Dislocation Kinetics Simulation

$$+ \begin{cases} M \frac{4}{\pi^{1.5}} \cdot \frac{T_L}{bd_s} \sqrt{f(1-f_p)} \sqrt{\left(\frac{\pi d_s \Gamma_{APB}}{2T_L} - 1 \right)} & \text{strong coupling} \\ M \left[\left(\frac{\Gamma_{APB}}{2b} \right)^{1.5} \sqrt{\frac{2bd_s f(1-f_p)}{T_L}} \cdot \frac{4}{\pi^{1.5}} - \frac{\Gamma_{APB} f(1-f_p)}{2b} \right] & \text{weak coupling} \end{cases}$$

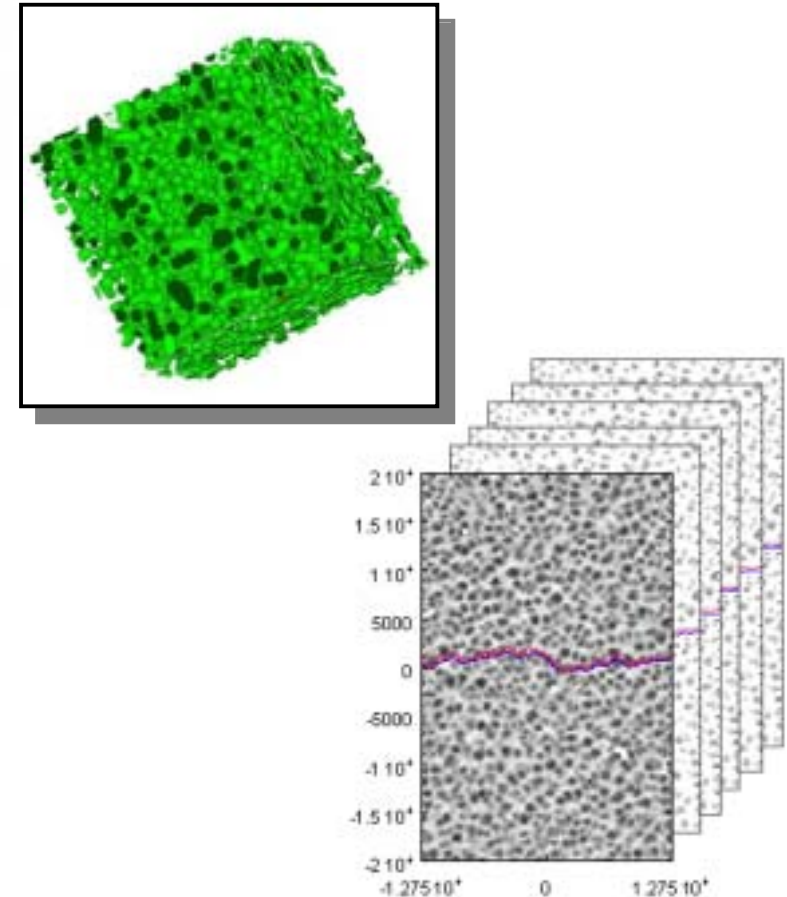
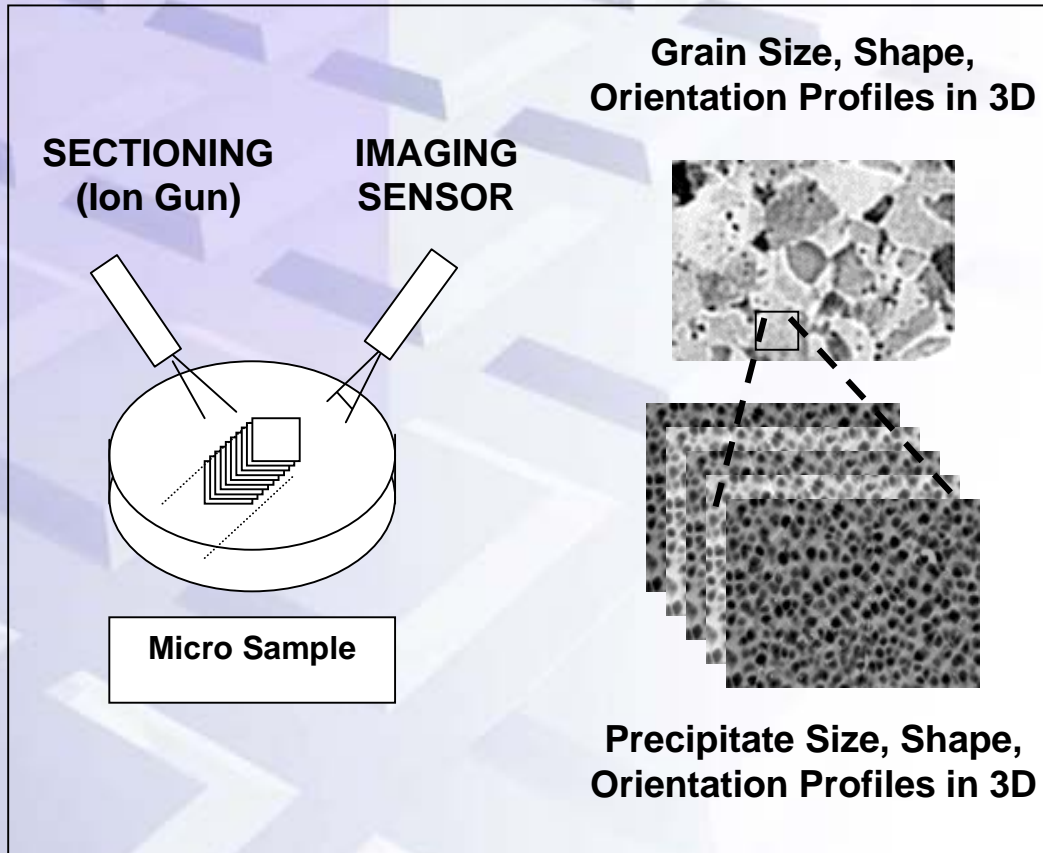
see Reppich

Obtain by FEM Simulation of Grain Distribution Effects

$$+ f_p \left[\sigma(T)_{Ni_3Al} + \sum_i \left(\frac{dc}{dC_i} C_i \right) \right] + f_p k_y^{\gamma'} \frac{1}{\sqrt{d_{\gamma'}}} + (1 - f_p) k_y^{\gamma} \frac{1}{\sqrt{d_{\gamma}}}$$

Numeric methods need and interface to AIM system

Unknown New Materials



3D sectioning experiments

Advanced simulation & experiments

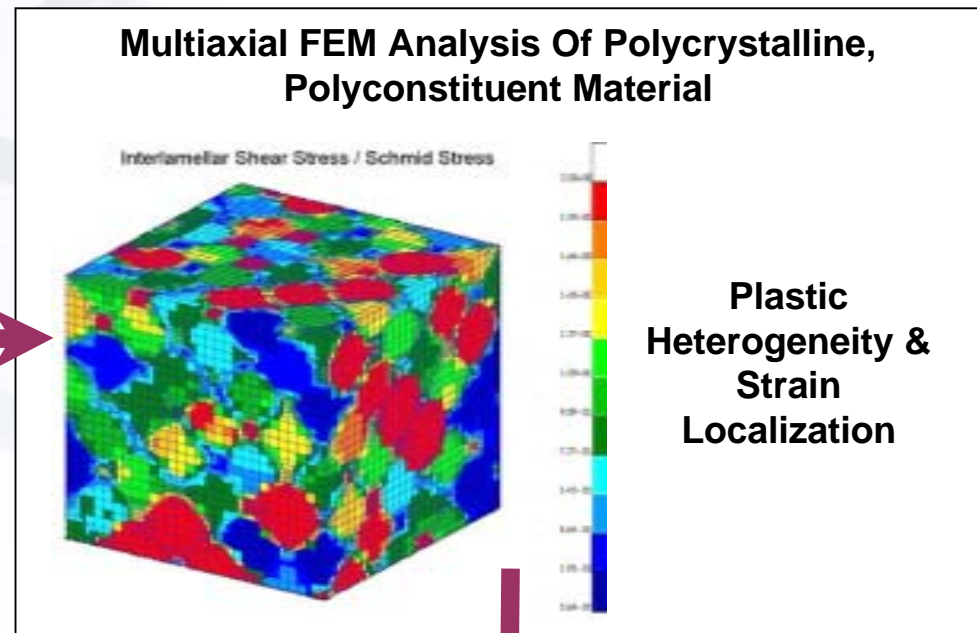
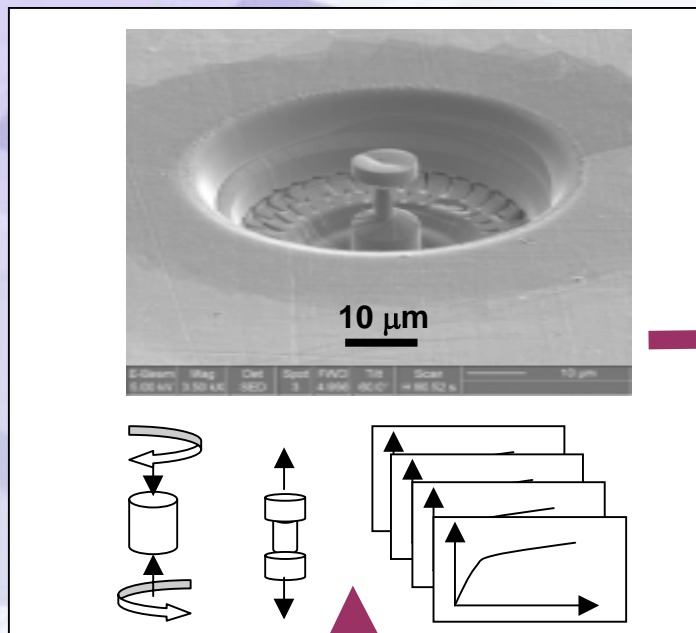
Small-scale property measurements

⇒ **3D virtual structure representations**

⇒ **intrinsic grain-level properties**

⇒ **model parameterization**

Treating Unknown New Materials



Properties of Representative Volume Element (RVE) From Mesoscale and Analytical Tools

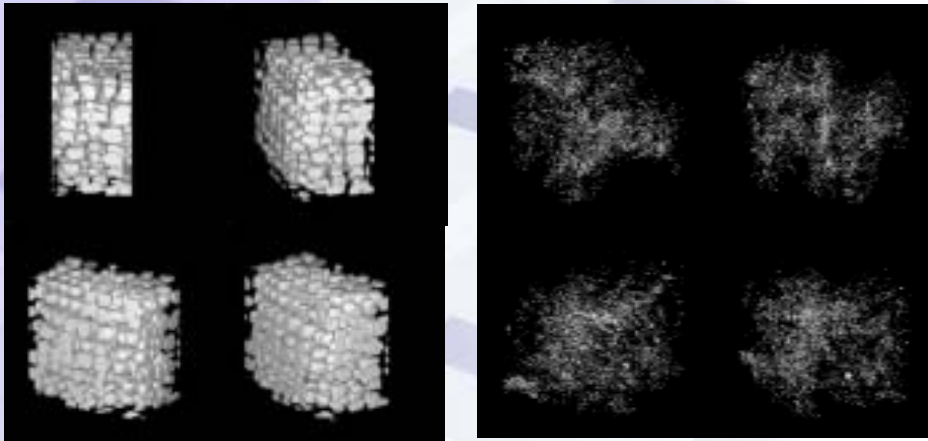
$$\dot{\tau} = \left\{ h - \left(\frac{\tau - \tau_o}{\tau_s - \tau_o} \right) h \right\} \left(\frac{\dot{\gamma}}{\dot{\gamma}_o} \right)^m$$

τ

γ

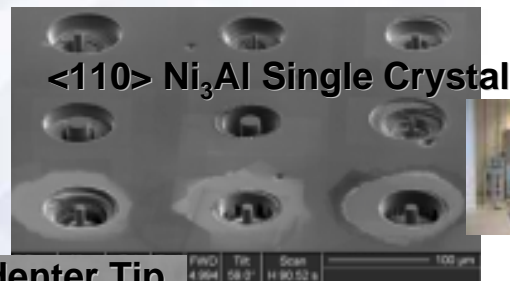
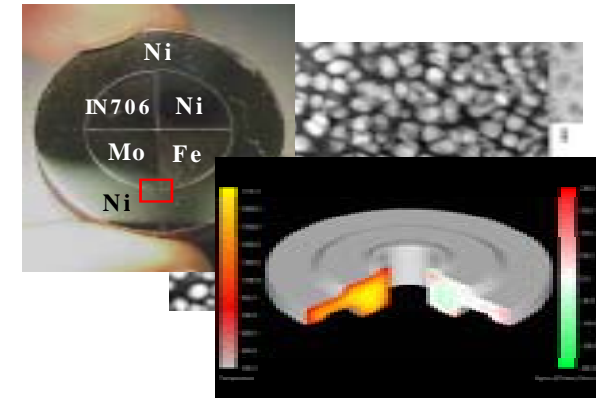
Microstructure-Sensitive Representations (UMATs for 'intrinsic material' RVEs; results used in Ramberg-Osgood or Walker-like forms, or "Curve Generator," etc)

Efficient Experiments for New Materials

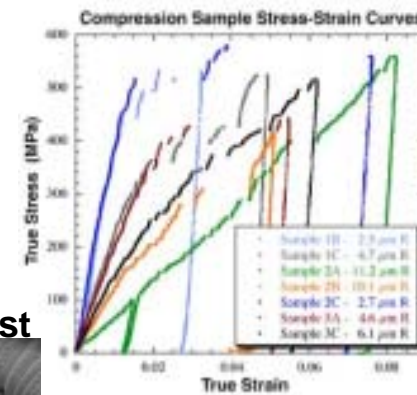
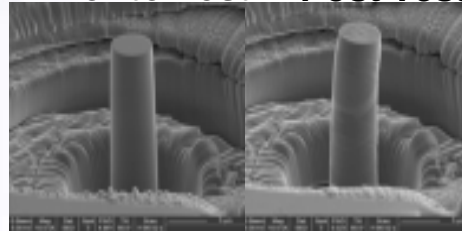


3-Dimensional Characterization of γ' and Carbides

Rapid Experiments, Modeling, & Characterization



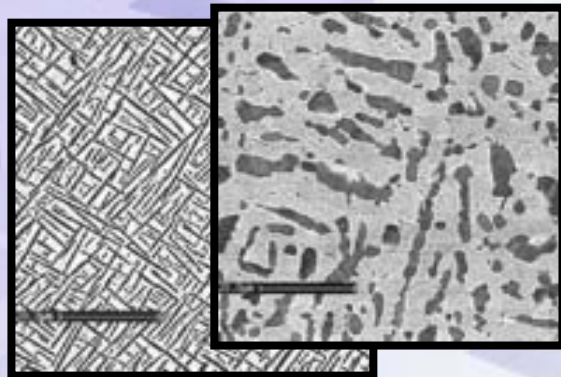
Prior to Test Post Test



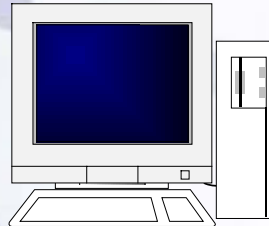
Micro- & Nano-Scale Property Measurement

Unprecedented Novel & Efficient Experiments Emerging!

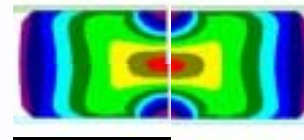
Payoff: Materials & System Prognostics



Materials



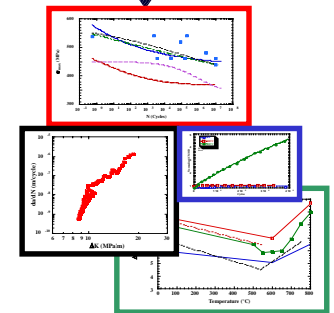
Mathematics



Experiment



Experience



Property Database

Mathematics

State Awareness

Failure Physics

Data Fusion

Reasoning System

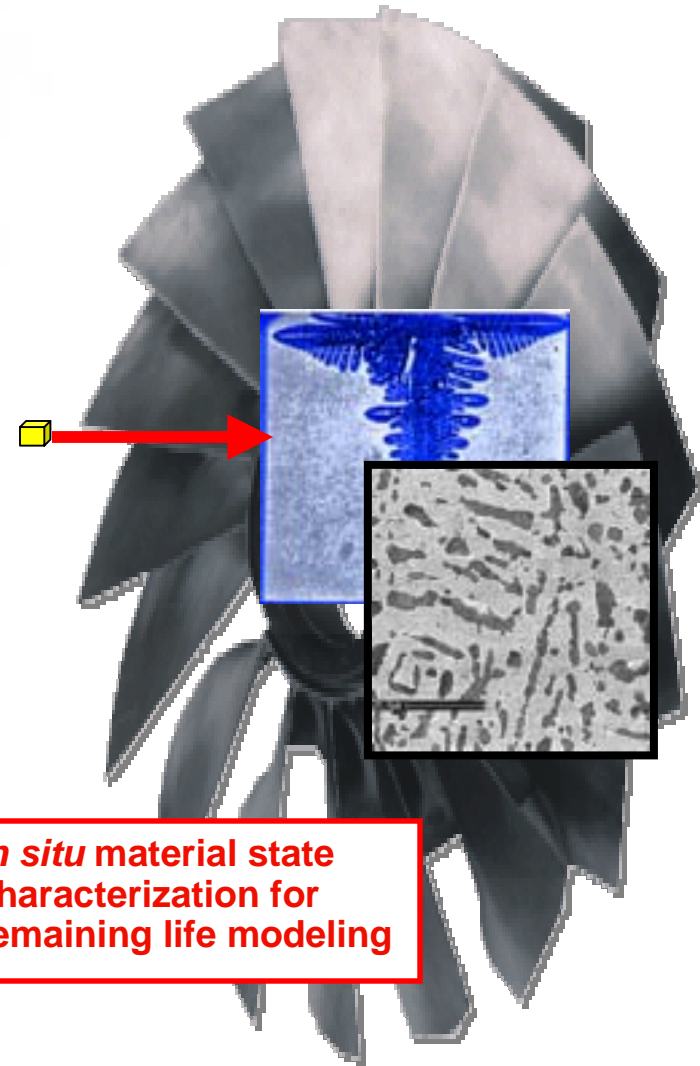


Combat System Readiness

Prognostics

Material State Definition

- Characterize each disk's microstructure and damage state at the mesoscale
- Utilize DARPA/AF AIM technology – stochastic life prediction
- Material state sensing
 - Electron backscatter diffraction (EBSD)
 - Acoustic attenuation
 - Others...
- Define the probability of cracking for each disk



MS & E Paradigm

